



Designation: C1720 – 11

Standard Test Method for Determining Liquidus Temperature of Immobilized Waste Glasses and Simulated Waste Glasses¹

This standard is issued under the fixed designation C1720; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reapproval. A superscript epsilon (ϵ) indicates an editorial change since the last revision or reapproval.

1. Scope

1.1 These practices cover procedures for determining the liquidus temperature (T_L) of nuclear waste, mixed nuclear waste, simulated nuclear waste, or hazardous waste glass in the temperature range from 600°C to 1600°C. This method differs from Practice C829 in that it employs additional methods to determine T_L . T_L is useful in waste glass plant operation, glass formulation, and melter design to determine the minimum temperature that must be maintained in a waste glass melt to make sure that crystallization does not occur or is below a particular constraint, for example, 1 volume % crystallinity or $T_{1\%}$. As of now, many institutions studying waste and simulated waste vitrification are not in agreement regarding this constraint (1).

1.2 Three methods are included, differing in (1) the type of equipment available to the analyst (that is, type of furnace and characterization equipment), (2) the quantity of glass available to the analyst, (3) the precision and accuracy desired for the measurement, and (4) candidate glass properties. The glass properties, for example, glass volatility and estimated T_L , will dictate the required method for making the most precise measurement. The three different approaches to measuring T_L described here include the following: (A) *Gradient Temperature Furnace Method (GT)*, (B) *Uniform Temperature Furnace Method (UT)*, and (C) *Crystal Fraction Extrapolation Method (CF)*. This procedure is intended to provide specific work processes, but may be supplemented by test instructions as deemed appropriate by the project manager or principle investigator. The methods defined here are not applicable to glasses that form multiple immiscible liquid phases. Immiscibility may be detected in the initial examination of glass during sample preparation (see 9.3). However, immiscibility may not become apparent until after testing is underway.

1.3 The values stated in either SI units or inch-pound units are to be regarded separately as standard. The values stated in each system may not be exact equivalents; therefore, each

system shall be used independently of the other. Combining values from the two systems may result in non-conformance with the standard.

1.4 *This standard does not purport to address all of the safety concerns, if any, associated with its use. It is the responsibility of the user of this standard to establish appropriate safety and health practices and determine the applicability of regulatory limitations prior to use.*

2. Referenced Documents

2.1 ASTM Standards:²

- C162 Terminology of Glass and Glass Products
 - C829 Practices for Measurement of Liquidus Temperature of Glass by the Gradient Furnace Method
 - D1129 Terminology Relating to Water
 - D1193 Specification for Reagent Water
 - E177 Practice for Use of the Terms Precision and Bias in ASTM Test Methods
 - E691 Practice for Conducting an Interlaboratory Study to Determine the Precision of a Test Method
 - E2282 Guide for Defining the Test Result of a Test Method
- ### 2.2 Other Documents:
- SRM-773 National Institute for Standards and Technology (NIST) Liquidus Temperature Standard
 - SRM-674b NIST X-Ray Powder Diffraction Intensity Set for Quantitative Analysis by X-Ray Diffraction (XRD)
 - SRM-1976a NIST Instrument Response Standard for X-Ray Powder Diffraction
 - Z540.3 American National Standards Institute/National Conference of Standards Laboratories (ANSI/NCSL) Requirements for the Calibration of Measuring and Test Equipment

3. Terminology

3.1 Definitions:

3.1.1 *air quenching*—to pour or place a molten glass specimen on a surface, for example, a steel plate, and cool it to the solid state.

¹ This test method is under the jurisdiction of ASTM Committee C26 on Nuclear Fuel Cycle and is the direct responsibility of Subcommittee C26.13 on Spent Fuel and High Level Waste.

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² For referenced ASTM standards, visit the ASTM website, www.astm.org, or contact ASTM Customer Service at service@astm.org. For *Annual Book of ASTM Standards* volume information, refer to the standard's Document Summary page on the ASTM website.

3.1.2 *anneal*—to prevent or remove materials processing stresses in glass by controlled cooling from a suitable temperature, for example, the glass transition temperature (T_g) (modified from Terminology C162).

3.1.3 *annealing*—a controlled cooling process for glass designed to reduce thermal residual stress to an acceptable level and, in some cases, modify structure (modified from Terminology C162).

3.1.4 *ASTM Type I water*—purified water with a maximum total matter content including soluble silica of 0.1 g/m³, a maximum electrical conductivity of 0.056 μΩ/cm at 25°C and a minimum electrical resistivity of 18 MΩ × cm at 25°C (see Specification D1193 and Terminology D1129).

3.1.5 *cleaning glass*—glass or flux used to remove high viscosity glass, melt insolubles, or other contamination from platinum-ware.

3.1.6 *crystallize*—to form or grow, or both, crystals from a glass melt during heat-treatment or cooling.

3.1.7 *crystallization*—the progression in which crystals are first nucleated and then grown within a host medium. Generally, the host may be a gas, liquid, or another crystalline form. However, in this context, it is assumed that the medium is a glass melt.

3.1.8 *crystallization front*—the boundary between the crystalline and crystal-free regions in a test specimen that was subjected to a temperature gradient heat-treatment.

3.1.9 *furnace profiling*—the process of determining the actual temperature inside of a furnace at a given location; this involves different processes for different types of furnaces.

3.1.10 *glass*—an inorganic product of fusion that has cooled to a rigid condition without crystallizing (see Terminology C162); a noncrystalline solid or an amorphous solid (2).³

3.1.11 *glass ceramic*—solid material, partly crystalline and partly glassy (see Terminology C162).

3.1.12 *glass sample*—the material to be heat-treated or tested by other means.

3.1.13 *glass specimen*—the material resulting from a specific heat treatment.

3.1.14 *glass transition temperature (T_g)*—on heating, the temperature at which a glass transforms from a solid to a liquid material, characterized by the onset of a rapid change in several properties, such as thermal expansivity.

3.1.15 *gradient furnace*—a furnace in which a known temperature gradient is maintained between the two ends.

3.1.16 *hazardous waste glass*—a glass composed of glass forming additives and hazardous waste.

3.1.17 *homogeneous glass*—a glass that is a single amorphous phase; a glass that is not separated into multiple amorphous phases.

3.1.18 *inhomogeneous glass*—a glass that is not a single amorphous phase; a glass that is either phase separated into multiple amorphous phases or is crystallized.

3.1.19 *liquidus temperature*—the maximum temperature at which equilibrium exists between the molten glass and its primary crystalline phase.

3.1.20 *melt insoluble*—a crystalline, amorphous, or mixed phase material that is not appreciably soluble in molten glass, for example, noble metals, noble metal oxides.

3.1.21 *mixed waste*—waste containing both radioactive and hazardous components regulated by the Atomic Energy Act (AEA) (3) and the Resource Conservation and Recovery Act (RCRA) (4), respectively; the term “radioactive component” refers to the actual radionuclides dispersed or suspended in the waste substance (5).

3.1.22 *mold*—a pattern, hollow form, or matrix for giving a certain shape or form to something in a plastic or molten state.

Webster’s⁴

3.1.23 *nuclear waste glass*—a glass composed of glass-forming additives and radioactive waste.

3.1.24 *observation*—the process of obtaining information regarding the presence or absence of an attribute of a test specimen or of making a reading on a characteristic or dimension of a test specimen (see Terminology E2282).

3.1.25 *phase separated glass*—a glass containing more than one amorphous phase.

3.1.26 *preferred orientation*—when there is a stronger tendency for the crystallites in a powder or a texture to be oriented more one way, or one set of ways, than all others. This is typically due to the crystal structure.

IUCr⁵

3.1.27 *primary phase*—the crystalline phase at equilibrium with a glass melt at its liquidus temperature.

3.1.28 *radioactive*—of or exhibiting radioactivity; a material giving or capable of giving off radiant energy in the form of particles or rays, for example, α, β, and γ, by the disintegration of atomic nuclei; said of certain elements, such as radium, thorium, and uranium and their products.

American Heritage⁶
Webster’s⁷

3.1.29 *Round-Robin*—an interlaboratory and intralaboratory testing process to develop the precision and bias of a procedure.

3.1.30 *section*—a part separated or removed by cutting; a slice, for example, representative thin section of the glass specimen.

Webster’s⁴

3.1.31 *set of samples*—samples tested simultaneously in the same oven.

3.1.32 *simulated nuclear waste glass*—a glass composed of glass forming additives with simulants of, or actual chemical species, or both, in radioactive wastes or in mixed nuclear wastes, or both.

³ The boldface numbers in parentheses refer to a list of references at the end of this standard.

⁴ Webster’s New Universal Unabridged Dictionary, 1979.

⁵ IUCr Online Dictionary of Crystallography, 2011.

⁶ American Heritage Dictionary, 1973.

⁷ Webster’s New Twentieth Century Dictionary, 1973.

3.1.33 *standard*—to have the quality of a model, gage, pattern, or type. **Webster’s⁷**

3.1.34 *standardize*—to make, cause, adjust, or adapt to fit a standard (**5**); to cause to conform to a given standard, for example, to make standard or uniform. **Webster’s⁷**

3.1.35 *surface tension*—a property, due to molecular forces, by which the surface film of all liquids tends to bring the contained volume into a form having the least possible area.

3.1.36 *test determination*—the value of a characteristic or dimension of a single test specimen derived from one or more observed values (see Terminology **E2282**).

3.1.37 *test method*—a definitive procedure that produces a test result (see Terminology **E2282**).

3.1.38 *test observation*—see *observation*.

3.1.39 *test result*—the value of a characteristic obtained by carrying out a specific test method (see Terminology **E2282**).

3.1.40 *uniform temperature furnace*—a furnace in which the temperature is invariant over some defined volume and within some defined variance.

3.1.41 *vitriification*—the process of fusing waste with glass making chemicals at elevated temperatures to form a waste glass (see Terminology **C162**).

3.1.42 *volatility*—the act of one or more constituents of a solid or liquid mixture to pass into the vapor state.

3.1.43 *waste glass*—a glass developed or used for immobilizing radioactive, mixed, or hazardous wastes.

3.2 Abbreviations:

3.2.1 *AEA*—Atomic Energy Act

3.2.2 *ANSI*—American National Standards Institute

3.2.3 *ASTM*—American Society for Testing and Materials

3.2.4 *CF*—crystal fraction extrapolation

3.2.5 *C_F*—crystal fraction in a sample or specimen

3.2.6 *EDS*—energy dispersive spectrometry

3.2.7 η —viscosity

3.2.8 *FWHM*—full width of a peak at half maximum

3.2.9 *GF*—gradient temperature furnace

3.2.10 *GT*—gradient temperature

3.2.11 *HF*—hydrofluoric acid

3.2.12 *HLW*—high-level waste

3.2.13 *ID*—identification

3.2.14 *NBS*—National Bureau of Standards

3.2.15 *NCSL*—National Conference of Standards Laboratories

3.2.16 *NIST*—National Institute for Standards and Technology (formerly NBS)

3.2.17 *OM*—optical microscope or optical microscopy

3.2.18 *PDF*—powder diffraction file

3.2.19 *RCRA*—Resource Conservation and Recovery Act

3.2.20 *RIR*—relative intensity ratio

3.2.21 *RLM*—reflected light microscopy

3.2.22 *SEM*—scanning electron microscope or scanning electron microscopy

3.2.23 *SRM*—Standard Reference Material

3.2.24 *T_{1%}*—temperature where glass contains 1 volume % of a crystalline phase

3.2.25 *T_a*—primary UT measurement above *T_L*

3.2.26 *T_c*—primary UT measurement below *T_L*

3.2.27 *T_g*—glass transition temperature

3.2.28 *T_L*—liquidus temperature

3.2.29 *TLM*—transmitted light microscopy

3.2.30 *T_M*—melting temperature for glass preparations

3.2.31 *UF*—uniform temperature furnace

3.2.32 *UT*—uniform temperature

3.2.33 *WC*—tungsten carbide

3.2.34 *XRD*—X-ray diffraction

4. Summary of Test Method

4.1 This procedure describes methods for determining the *T_L* of waste or simulated waste glasses. Temperature is defined as the maximum temperature at which equilibrium exists between the molten glass and its primary crystalline phase. In other words, *T_L* is the maximum temperature at which a glass melt crystallizes. **Fig. 1** illustrates an example *T_L* for a simple two-component liquid on a binary phase diagram.

4.1.1 (*A*) *Gradient Temperature Furnace Method (GT)*—This method is similar to Practice **C829**, “Standard Practices for Measurement of Liquidus Temperature of Glass by the Gradient Furnace Method,” though it has been modified to meet the specific needs of waste and simulated waste glass measurements. The most pronounced differences between this method and the Practice **C829** “boat method” are the sample preparation and examination procedures.

4.1.1.1 Samples are loaded into a boat, for example, platinum alloy (**Fig. 2**) with a tight-fitting lid, and exposed to a linear temperature gradient in a gradient furnace (**Fig. 3**) for a fixed period of time. The temperature, as a function of distance, *d*, along the sample, is determined by its location within the GF, and the *T_L* is then related to the location of the crystallization front in the heat-treated specimen (**Fig. 4**).

4.1.1.2 Following the heat-treatment, the specimen should be annealed at or near the glass transition, *T_g*, of the glass (this should be previously measured or estimated) to reduce specimen cracking during cutting and polishing.

4.1.1.3 The specimen should then be scored or marked to signify the locations on the specimen located at different depths into the gradient furnace, that is, locations heat-treated at specific temperatures.

4.1.1.4 If the specimen is optically transparent, it can be observed with transmitted light (that is, transmitted light microscopy or TLM) or reflected light microscopy (RLM) to look for bulk or surface crystallization, respectively. If the specimen is not optically transparent or is barely optically transparent (for example, in high iron glasses with high quantities of FeO), a cut or fractured section of the glass can be polished very thin (that is, a thin section can be made) to allow

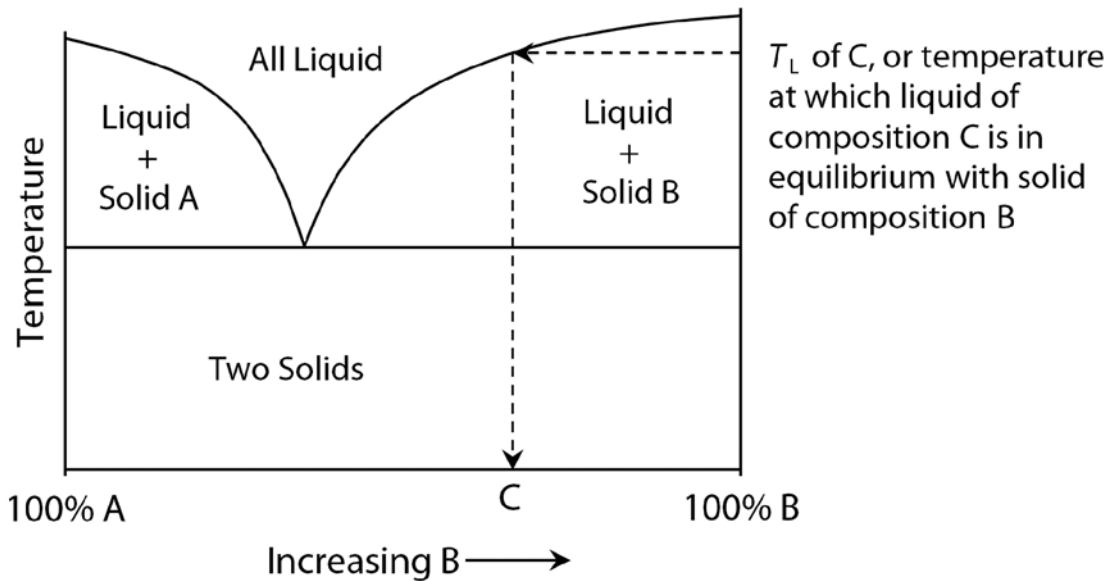


FIG. 1 Binary Phase Diagram of Components A and B with T_L of Composition C Highlighted

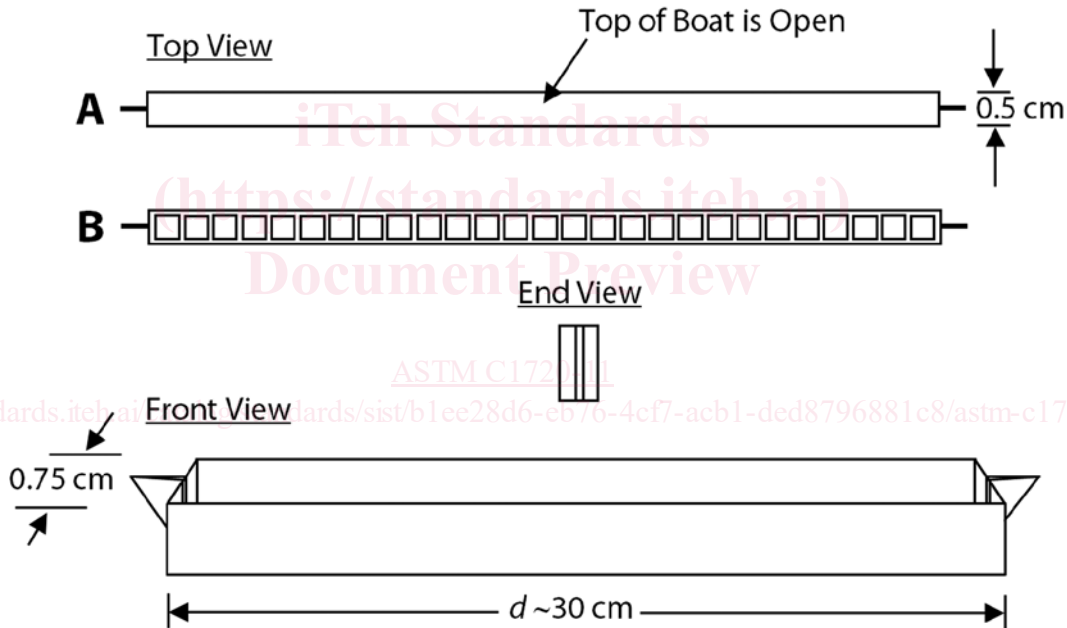


FIG. 2 GF Boat Diagram: (A) Single Chamber Crucible Design (B) Single Chamber Design Loaded with a Set of Samples (that is, Smaller Crucibles)

for observation. Another option for surface observations is scanning electron microscopy (SEM). This method provides a quick measurement of T_L in the absence of convective flow of glass in the GF, which distorts the crystallization front (that is, the crystallization front shall not be constant with melt height).

4.1.1.5 The temperature gradient and increased volatility at higher temperatures cause gradients in surface tension, which in turn cause convective flow. This method is ideal for glasses with a T_L less than roughly 1000°C or glasses with a low volatility near the T_L . If the temperature range spanned by the crystallization front is too high for the desired tolerance, the UT or CF methods (Method B or C) should be used for a more precise T_L measurement. Method A is not easily used to

measure the T_L on radioactive glasses because of the size of the GF and the complicated sample analysis required. This method is not recommended for glasses with a T_L in a temperature range of very low glass viscosity (that is, $\eta < 50 \text{ Pa} \times \text{s}$).

4.1.2 (B) *Uniform Temperature Furnace Method (UT)*— This method is similar to the methods used in phase diagram determination and can be used for more precise measurements than those determined with (A) *Gradient Temperature Furnace Method (GT)*.

4.1.2.1 In this method, a glass sample is loaded into a crucible (for example, platinum alloy, see Fig. 5) with a tight-fitting lid and subjected to temperatures for a fixed period of time (for example, $24 \pm 2 \text{ hrs}$). Following heat-treatment,



FIG. 3 Photograph of Typical Gradient Temperature Furnace

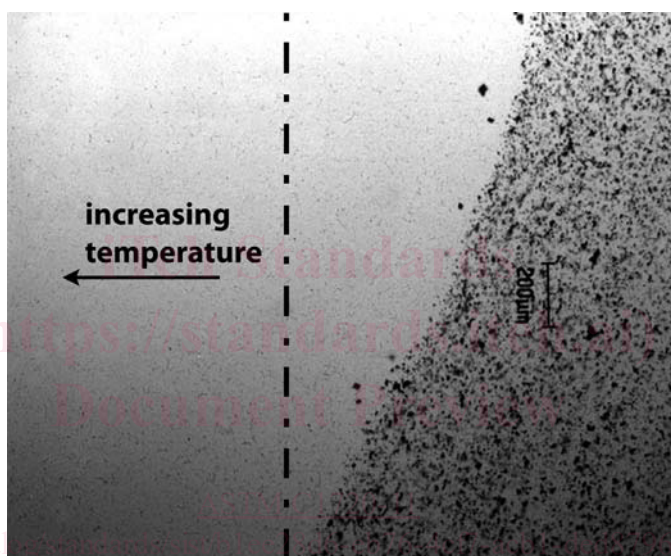


FIG. 4 OM Micrograph of the Crystallization Front in a GT Specimen

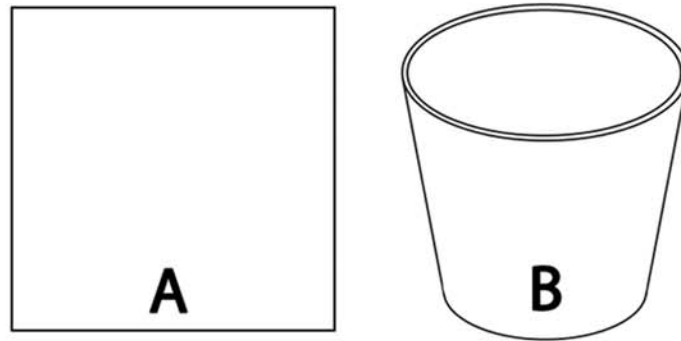
the specimen can be observed by optical microscopy (OM) for the appearance or absence of crystalline or other undissolved materials with methods similar to those previously described (4.1.1).

4.1.2.2 The T_L is then given by the temperature range between the highest temperature at which a specimen contains crystals (T_c) and the lowest temperature without crystals in the specimen (T_a); the T_L is then typically defined as the average of T_a and T_c .

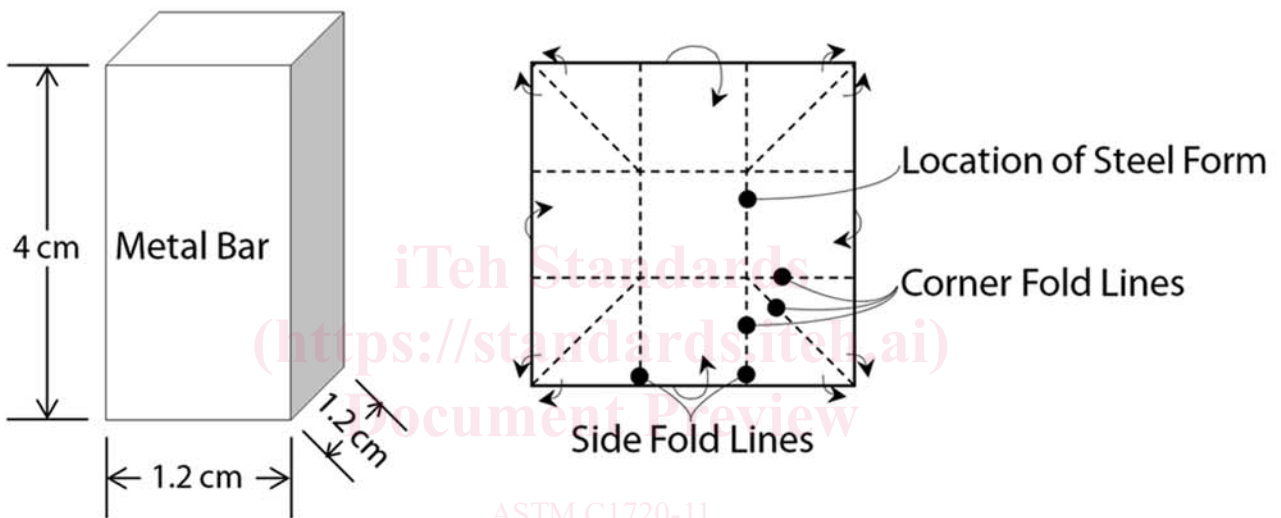
4.1.2.3 This method is more time consuming as it requires multiple heat-treatments than the GT method, though it minimizes the effects of volatility and eliminates the convection-driven uncertainty in crystallization front measurements. This method is used for high precision measurements (on the order of $\pm 5^\circ\text{C}$), is more easily applied to radioactive glasses, and is capable of measuring T_L values as high as 1600°C with typical high-temperature furnaces (for example, furnaces with MoSi_2 heating elements) though higher with specialized equipment and high-temperature crucibles. This method may be used for glasses with a high volatility near T_L under certain circumstances.

4.1.3 (C) *Crystal Fraction Extrapolation Method (CF)*—This method is an alternate method that uses a UT specimen to measure the crystal fraction, C_F (in mass % or volume %), of a crystalline phase or phases in a sample heat-treated at multiple temperatures, $T \ll T_L$. The C_F at each temperature is measured with XRD, RLM, TLM, or SEM, or combinations thereof, by mass % or by volume %, or both, and then T_L is achieved by extrapolating C_F as a function of temperature to zero crystals. This method is more suited for glasses with a higher volatility near the T_L than the previous methods. When multiple crystalline phases are present, XRD is an effective method for quantifying C_F as a function of temperature and is very effective at determining the T_L of each phase independently; this would be more difficult with Methods A or B. The C_F method yields the additional benefit of equilibrium crystal fractions as a function of temperature, which can sometimes tend to be non-linear at $C_F > 5$ to 10 mass % crystallinity for most crystalline phases. Different techniques for the C_F method are described below.

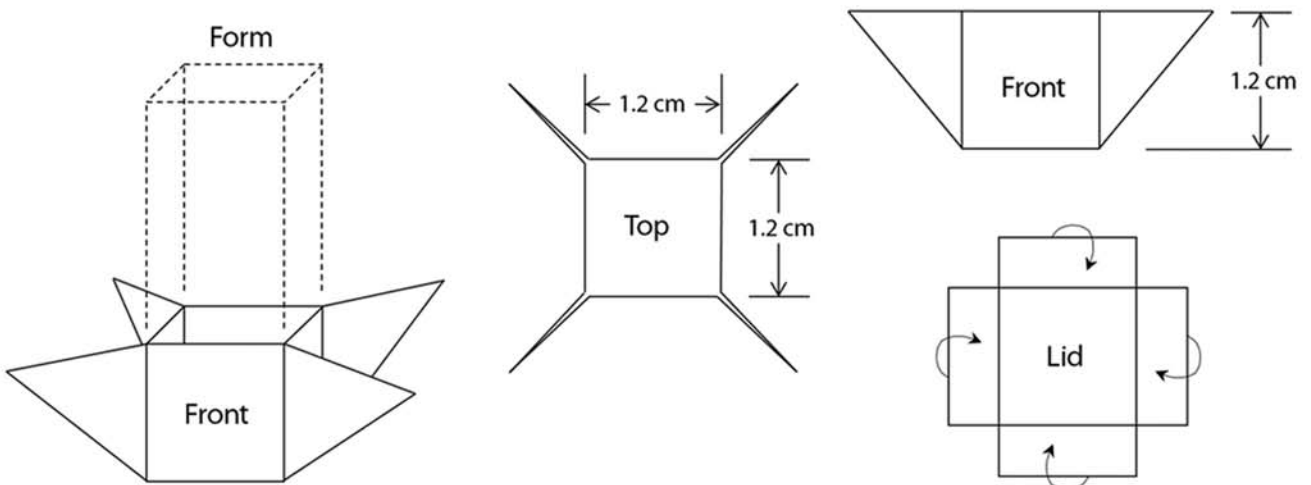
4.1.3.1 *Volume Fraction of Crystal(s) in the Specimen (12.4.2)*—With TLM, RLM, or SEM as well as image analysis



(1) 3.6- x 3.6-cm square piece of foil (A) or conical thimble (B) made of inert material, for example, platinum alloy



(2) For the cubic crucible, take foil in (1) and draw an "X" pattern from corner to corner (excluding the center square) to help locate the form used and where to fold the corners.



(3) Fold the corners along the diagonal lines. Then fold the sides up next to the form.

FIG. 5 UF Crucible Schematic

software (to define area fractions of glass and crystal phases), it is possible to measure the area fraction of crystals in an image or micrograph of the specimen, typically a micrograph. The area fraction is then equivalent to the volume fraction if the image is representative of the specimen, and the effective depth of the image is insignificant. If this process is done at different temperatures, the T_L can be extrapolated as a function of temperature.

NOTE 1—The mass fraction of crystals in the specimen can be estimated if the density of the glass and the crystal(s) is known.

4.1.3.2 *Number Fraction of Crystal(s) in the Specimen (12.4.3)*—In the same fashion as described in 4.1.3.1, count the number of crystals in an image or micrograph of the specimen at different temperatures. If this process is done at different temperatures, the T_L can be extrapolated as a function of temperature.

4.1.3.3 *Mass Fraction of Crystal(s) in the Specimen by Adding a Known Crystalline Phase (12.4.4)*—Adding a known mass fraction of a known, standard crystalline material (for example, NIST SRM-674b) allows the standardization of the XRD pattern. The standards and the unknown specimen should be run in independently before mixing to verify that there is not overlap between the peaks of the standard and the peaks in the unknown specimen because this will make quantification difficult and less accurate. The standardized pattern can then be used to generate quantitative (if the crystal structure has been refined) or semi-quantitative (if the crystal structure has not been refined) C_F analysis with Rietveld (6-8) refinement software or the relative intensity ratio (RIR) method (12.4.5).

4.1.3.4 *Mass Fraction of Crystal(s) in the Specimen by Comparing it to the Calibration Curve (12.4.5)*—In this method, samples with known concentrations of the crystalline phases being analyzed are prepared and tested using XRD. The peak area's (full width at half maximum or FWHM, total crystal peak area, or highest peak area) and known crystal fractions are used to generate a calibration curve. The peak area of the unknown specimen is then used in the calibration equation to determine a quantitative (if interpolated) or semi-quantitative (if extrapolated) crystal fraction.

4.1.3.5 *Volume Fraction of Crystal(s) in the Specimen With C_F Data From XRD Analysis*—Commonly, melter constraints are in terms of a volume % of crystallinity, for example, 1 volume % or $T_{1\%}$. Once C_F data are obtained in mass % by XRD, the remaining mass of glass, m_g , is calculated as a difference given by

$$m_g = m_t - \sum_{i=1}^N m_{c,i} \quad (1)$$

where:

m_t = the total mass (that is, the value is normalized to one and thus component values are mass fractions), and
 $m_{c,i}$ = the mass fraction of the i -th crystalline phase observed and quantified by XRD.

By converting the mass fractions of the i -th component additives, m_i , into mole fractions, M_i , the density of glass, ρ_g , can be computed with the following expression:

$$\rho_g = \frac{\sum_{i=1}^N M_i m_{m,i}}{\sum_{i=1}^N M_i V_{M,i}} \quad (2)$$

where:

$m_{m,i}$ = the molecular mass of the i -th oxide, and
 $V_{M,i}$ = the molar volume of the i -th component additive explained elsewhere (9).

The total volume of each heat treatment, V_{HT} , is calculated with

$$V_{HT} = \frac{m_g}{\rho_g} + \frac{\sum_{i=1}^N m_{c,i}}{\rho_{c,i}} \quad (3)$$

where:

$\rho_{c,i}$ = the density of the i -th crystalline component.

The volume % of the i -th crystalline component, $V_{c,i}$, in the heat-treated specimen is denoted by

$$V_{c,i} = 100 \times \frac{m_{c,i}}{(\rho_{c,i} \times V_{HT})} \quad (4)$$

The values of $V_{c,i}$ can then be plotted as a function of temperature and a linear correlation fit to the data with

$$V_{c,i} = m \times T + b \quad (5)$$

where:

$T_{1\%} = (V_{c,i} - b)/m$ when $V_{c,i} = 1$ ($T_{1\%}$)

5. Significance and Use

5.1 This procedure can be used for (but is limited to) the following applications:

- (1) support glass formulation development to make sure that processing criteria are met,
- (2) support production (for example, processing or troubleshooting), and
- (3) support model validation.

6. Apparatus

6.1 Equipment for the GT Method:

6.1.1 Resistance-heated tubular gradient furnace capable of achieving temperatures of 550 to 1150°C with gradients in the range of roughly 1°C/mm (Fig. 3). For glasses with an estimated $T_L > 1150^\circ\text{C}$, furnaces with elements capable of high temperatures need be used, for example, MoSi₂.

6.1.2 Calibrated thermocouple and temperature readout device appropriate to the estimated temperature range that will be used for testing. Type K can be used within 95 to 1260°C, Type R can be used within 870 to 1450°C, and Type S can be used within 980 to 1450°C without special calibrations or qualifications.

6.1.3 Resistance furnace and controller used for annealing (capable of maintaining constant temperatures between 400 and ~900°C) with a temperature accuracy of 10°C.

6.1.4 Specimen boat made of material inert to the sample (for example, platinum alloy) with approximate dimensions of 0.5 × 1 × 10 to 30 cm (width × height × length), respectively; an example specimen boat is shown in Fig. 2. If the test glass viscosity is below 5 Pa × s at the measurement temperature, it is recommended that a round-based crucible be used. A

separate option with Method A is to fill the long boat with several small individual boats with individual lids (Fig. 2-B)

6.1.5 Diamond cutoff saw.

6.1.6 Variable speed polisher.

6.1.7 Silicone rubber mold for mounting of GT glass specimen in epoxy.

6.1.8 OM for TLM and RLM.

6.1.9 Scanning electron microscope with energy dispersive spectrometer.

6.1.10 X-ray diffractometer.

6.2 *Equipment Needed for the UT Method:*

6.2.1 Resistance furnace capable of maintaining constant temperatures $T \sim 550$ to 1600°C (that is, MoSi_2 heating elements) or furnace capable of $T \leq 1200^\circ\text{C}$ for glasses with $T_L \leq 1150^\circ\text{C}$.

6.2.2 Calibrated thermocouple and temperature readout device appropriate to the estimated temperature range that will be used for testing (6.1.2).

6.2.3 Specimen boat (or crucible) and tight fitting lid made of material compatible with the sample (for example, platinum alloy) with suggested dimensions of $1.2 \times 1.2 \times 1.2$ cm (width \times height \times length, respectively) (Fig. 5-1A). Another option is a round-bottom, thimble-shaped crucible (Fig. 5-1B).

6.2.4 Diamond cutoff saw.

6.2.5 Variable speed polisher.

6.2.6 OM with variable power transmitted and reflected light.

6.2.7 SEM/energy dispersive spectrometry (EDS).

6.2.8 XRD.

6.3 Equipment needed for the CF method includes the same equipment as described previously in 6.2 because a UT specimen is required for the measurement technique, though additional materials are also required.

6.3.1 Image analysis software for measuring the C_F present in a micrograph collected with OM, SEM, etc.

6.3.2 Crystal structure/unit cell refinement software for quantifying crystal fractions by spiking in a known mass% of a known crystalline material.

6.3.3 Known crystalline material (for example, SRM-674b) that does not overlap with crystalline peaks in unknown specimen.

7. Reagents and Materials

7.1 Reagents and materials used in conjunction with the various methods outlined in this procedure.

7.1.1 *Reagents:*

7.1.1.1 ASTM Type 1 water.

7.1.1.2 Cleaning solvents, for example, ethanol, isopropanol, acetone.

7.1.1.3 Abrasive media for polishing, for example, SiC, diamond.

7.1.1.4 Glass microscope slides.

7.1.1.5 Glass cover slides.

7.1.1.6 Temperature sensitive adhesive.

7.1.1.7 Solvent-soluble adhesives, for example, methyl methacrylate-based adhesives.

7.1.1.8 Non-temperature sensitive adhesives (such as cyanoacrylate or other epoxy).

7.1.2 *Materials:*

7.1.2.1 Furnace appropriate to method being used, for example, GF, UF (required heating elements dependent on temperature needs).

7.1.2.2 Material for making crucibles or boats, for example, sheets of platinum alloy or pre-formed crucible(s).

7.1.3 *Calibrated Thermocouples*—Type K can be used within 95 to 1260°C , Type R can be used within 870 to 1450°C , and Type S can be used within 980 to 1450°C without special calibrations or qualifications.

7.1.3.1 Standard reference material for calibrating furnace, for example, SRM-773.

7.1.3.2 OM or SEM for making visual observations of heat-treated specimens.

7.1.3.3 XRD for making C_F measurements.

7.1.3.4 XRD standard reference material for peak location and C_F calibration (for example, SRM-1976a).

8. Hazards

8.1 The hazards associated with this procedure should be evaluated by each institution before conducting work.

8.2 The primary hazards encountered when following this procedure are sharp objects (for example, metal foil for crucibles, glass shards, and saws), high-temperature surfaces (for example, furnace surfaces, heat-treated specimens fresh out of a furnace, tongs used to remove specimens from a furnace), electrical hazards (for example, exposed heating elements such as MoSi_2), and radiation hazards (for example, if working with radioactive waste, when using XRD). When handling a glass specimen, protective gloves should be worn to prevent injury. The furnaces used for heat-treatment of the glass samples outlined in this procedure are at temperatures of 600 to 1600°C , and therefore temperature-resistant or insulated gloves should be worn when putting samples into the furnace as well as removing specimens from the furnace. Electrically insulating gloves should also be used in conjunction with (that is, underneath) the leather gloves to electrically isolate the user's hands from potential contact of the tongs or tweezers with exposed electrical elements used in removing heat-treated specimens. It is pertinent that the operator of the XRD is cautious of the hazards associated with the technique and is trained to the institution's safety procedures for operating the equipment.

9. Sampling, Test Specimens, and Test Units

9.1 Specific test instructions will contain all or part of the following information: preferred T_L measurement method, tolerance goals, estimated T_g (needed for Method A only), an estimated T_L or temperature range (based on model predictions), heat treatment time, and data recording requirements.

9.2 *GF Preparation:*

9.2.1 A gradient furnace is constructed of two or more independent heating zones, and thus the gradient can be adjusted as needed to obtain a low-pitched ($\Delta T/\Delta d$ is low, where T is temperature and d is distance from a reference point inside the furnace) or sharp gradient ($\Delta T/\Delta d$ is high) that is dependent on the crystallization rate of the sample ($\Delta C_F/\Delta T$).

If $\Delta C_F/\Delta T$ is low (for example, $\Delta C_F/\Delta T \leq 1$ mass % ΔC_F increase over $\geq 100^\circ\text{C}$ is considered low), the gradient can be low-pitched, and in cases where $\Delta C_F/\Delta T$ is high ($\Delta C_F/\Delta T \geq 1$ mass % ΔC_F increase over $\leq 10^\circ\text{C}$ is considered extremely high), the gradient can be high-pitched.

9.3 Sample Preparation for Methods A, B, and C:

9.3.1 Glass samples for T_L analysis are typically melted, ground to a powder and mixed, remelted, and then quenched on a steel plate. Once quenched, analyze the glass sample with OM, SEM, or XRD, or combinations thereof, to make sure that the sample is free of crystalline and immiscible glass phases. Melt insolubles (for example, noble metal oxides) are acceptable, but should be reported. If the sample is crystal free and homogeneous, then follow 9.3.2-9.3.4. However, if the glass is crystallized or otherwise inhomogeneous, then skip to step 9.3.5.

9.3.2 According to Practice C829, the particle sizes recommended for T_L determination of the SRM-773 glass with Method A (boat method) is < 0.85 mm (-20 mesh) and with Method B (perforated plate) is between 1.70 and 2.36 mm (+12/-8 mesh). However, in practice, glass particles that are too small (that is, ≤ 0.100 mm) when heat-treated can introduce a significant degree of bubbles into the melt, especially in moderate and high viscosity glasses ($\eta > 10$ Pa \times s), which can dramatically affect heat transfer as well as visibility through a heat-treated glass specimen. Also, it is difficult to clean glass particles that are too small (that is, ≤ 0.100 mm). Glass particles that are too large (that is, > 4 mm) will not fit in the previously described crucibles. Thus, the recommended particle size for these measurements is between 0.422 mm and 4 mm or (+40/-5 mesh); thus the glass should be sieved and this size retained. These sizes are used because sizes $\ll 0.422$ mm will promote crystal nucleation and growth during heat treatments, and sizes $\gg 4.0$ mm pose a issues when attempting to load glass into the crucible because the packing density is reduced significantly. Carefully crush the glass, being cautious not to introduce contamination (that is, no direct contact with steel). Use a mill or mortar and pestle composed of material harder than the glass (for example, SiC, WC, or equivalent) to crush the sample to the desired size.

9.3.3 Wash the sample by ultrasonic cleaning for 2 min in a clean glass beaker or equivalent container by submerging glass particles in ASTM Type 1 water, which fills the container above the glass by an equivalent volume. Decant the water and repeat the ultrasonic cleaning twice more (2 min each cleaning) with fresh ASTM Type 1 water. Ultrasonically clean the sample a fourth time for 2 min with ethanol. Decant the ethanol and dry the sample at $\geq 90^\circ\text{C}$ for ≥ 1 hr in an open beaker in an oven designed for drying combustibles. The washing steps can be performed using alternative, non-polar solvents (for example, pentane, hexane) if a reaction between water or the solvent and the glass is suspected.

9.3.4 Transfer the cleaned and dried glass sample into a clean, marked container or bag, being careful not to contaminate the glass with dust, dirt, oils, or salts or cross-contaminate the sample with other samples. Seal the container or bag and store in a clean, dry environment until ready for testing.

9.3.5 Glasses that are crystallized, inhomogeneous, or phase separated should be prepared by grinding the entire batch to a very fine powder. The grinding and mixing will best homogenize the glass. It is essential to reduce the effects of sample inhomogeneity when making T_L measurements.

10. Preparation of Apparatus

10.1 *Furnace Setup*—The furnace should be capable of sustaining temperatures that will be used for heat treatments with $\geq 50^\circ\text{C}$ between the furnace's maximum operating temperature and the heat-treatment temperature. The furnace should have a calibrated temperature monitoring capability. The furnace should have an over-temperature control to prevent damage to the furnace by potential heating past the maximum operating temperature of the furnace. See 6.1 and 6.2 for further information.

10.2 *Specimen Preparation for Analysis*—See 12.2.4 for instructions on preparing specimens for the GT method, 12.3.2 for instructions on preparing specimens for the UT method, and the 12.4 subsections for instructions on preparing specimens for the different CF methods.

10.3 Analysis Equipment:

10.3.1 *OM*—OM can be used to observe heat-treated specimens in TLM or RLM mode (depending on specimen optical transparency and morphology). For image analysis in Method C, the microscope should be equipped with a micrograph acquisition system (for example, digital camera).

10.3.2 *SEM*—Specimen preparation for general SEM observations typically requires that the specimen be coated with an electrically conductive coating (for example, C, Au, Pd) unless the SEM can analyze low-conductivity specimens. For high-resolution SEM micrograph acquisition, specimens can either be polished (best if done to optical quality) to expose the features of interest on a surface of the specimen, or they can remain unpolished.

10.3.3 *XRD*—Typical specimen preparation for XRD involves grinding a heat-treated specimen to a powder. To verify peak locations, the powdered specimen should be doped with an approved XRD standard, for example SRM-1976a.

11. Calibration and Standardization

11.1 *Calibration*—The test equipment, including thermocouples and thermocouple readouts, must be calibrated, at least annually, in accordance with a consensus standard, for example, ANSI/NCSL Z540.3.

11.1.1 Furnaces must be profiled for temperature at least once every six months and checked for accuracy at least once every six months during active projects. Profiling of the GF shall be performed according to Practice C829 (see 11.1.1.1).

11.1.1.1 The GF can be profiled by inserting a calibrated thermocouple into the furnace, while empty, and measuring the equilibrium temperature at different distances, d , from a location (typically a stopper inserted at the back end). Use the gradient furnace temperature profile to determine the length of the specimen boat and the position where the boat is placed in the gradient furnace. If the gradient is non-linear, the different heating zones can be adjusted accordingly until the desired gradient and gradient shape are achieved. The temperature

gradient in the GF should be close to linear ($\pm 1^\circ\text{C}$ over the temperature range of interest) with a gradient of no more than $1.2^\circ\text{C}/\text{mm}$. Then, the gradient furnace should be operated with standard reference materials for temperature calibration, for example, SRM-773.

11.1.1.2 To profile a UF, create a sample stage inside of the furnace in the middle of the hot zone of the furnace. Then, make sure that there are an adequate number of holes through the top of the furnace that are large enough to fit the width of a thermocouple (~ 0.6 cm) directly above the positions labeled on the sample stage. Holes not in use should be plugged to prevent heat loss and unwanted temperature gradients. If using Example (B) in Table, then nine holes must be made in the top of the furnace directly above the locations being profiled.

11.1.1.3 The furnace is to be profiled through a temperature range of a given test. For instance, if the furnace is going to be used to test samples in the range of 810 to 1290°C, then the furnace should be profiled at 800°C, 1300°C, and a regular temperature increment in between (for example, every 100°C from 800 to 1300°C). Note that not all thermocouples can be calibrated through this entire range, so make sure that a calibration curve is used for each type of thermocouple to extrapolate the actual temperature value from the voltage reading on the thermocouple readout if the thermocouple being used is outside of the range (for example, Type R/S at $T \geq 1450^\circ\text{C}$).

11.1.1.4 At each temperature, place the calibrated thermocouple through the hole in the top of the furnace and rest the end of the thermocouple at the location where the sample crucible shall be located on the sample stage. Note that electrical safety procedures must be followed when working near electrical hazards. Let the temperature come to thermal equilibrium (for example, 5 to 20 min) at each location and record the reading from the thermocouple in the profiling table (see example in Table). If a temperature value at a given location on the sample stage at a given temperature is $\pm 5^\circ\text{C}$ different from the average temperature over the other profiling locations, then data collected at that location at that temperature should not be used for the T_c/T_a values used to determine

T_L . Therefore, samples for T_c and T_a values used to determine T_L should be run at a location on the sample stage that is different from any locations that are out of tolerance.

11.1.2 The XRD should be calibrated every six months or at the completion of any maintenance. To do this, perform an XRD scan on a 2θ calibration standard (for example, SRM-1976a) and verify that the diffraction peak locations (that is, degrees, 2θ) and intensities match those of the standard. If peaks are not in the correct locations, then the instrument must be realigned.

11.2 *Measurement Control*—At least one standard glass with T_L traceable to a round robin study or NIST standard (that is, SRM-773) shall be tested with each new batch of T_L measurements or on a regular frequency to determine the accuracy of each furnace over time. The minimum frequency shall be measured once annually or with each change of furnace profile or gradient, whichever comes first. The measured value must be within the tolerance expected for the standard glass, or the furnace must be re-configured and the standard re-measured. The data from these tests should be maintained, plotted, and analyzed to check for trends, biases, or increases in variation as part of a defined measurement control program. This can provide continuous validation of the test method and basis for bias adjustments.

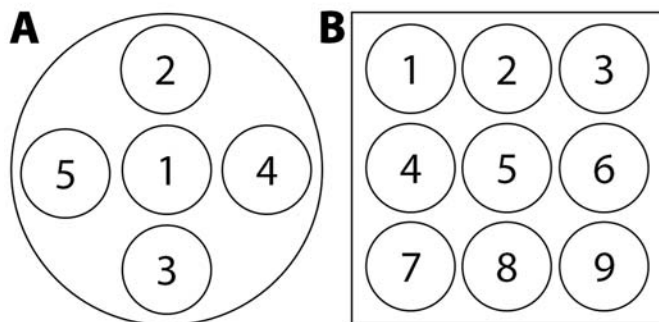
12. Procedure

12.1 Liquidus temperature measurements of a glass specimen shall be determined by one of three methods: (A) *Gradient Temperature Furnace Method (GT)*, (B) *Uniform Temperature Furnace Method (UT)*, or (C) *Crystal Fraction Extrapolation Method (CF)*. The appropriate method for the samples to be tested shall be specified in the applicable test instructions. For GT specimens, proceed to 12.2; for UT specimens, proceed to 12.3; for CF specimens, proceed to 12.4.

12.2 Gradient Temperature Furnace Method (GT):

12.2.1 Place test glass sample in a boat (6.1) and slide into a preheated and profiled gradient furnace (11.1.1.1) through the cooler end of the furnace. Position the boat in the furnace at the

TABLE 1 Furnace Profiling Diagram



Position:	①	②	③	④	⑤
800	801	804	802	803	803
900	901	903	903	903	904
1000	1001	1002	1003	1003	1004
1100	1103	1104	1104	1104	1103
1200	1204	1202	1202	1203	1203
1300	1304	1302	1302	1301	1301
1400	1401	1404	1401	1402	1408

NOTE 1—(A) Shows a circular sample stage example and (B) shows a square sample stage example. The tabulated data to the right of the diagrams shows how the thermocouple readouts are entered at each temperature for each position. Locations at temperatures that are more than $\pm 2^\circ\text{C}$ from the average temperatures collected at a specific temperature are to be omitted from use for T_a or T_c values—these values are to be labeled as red, bold, or underlined, or combinations thereof.